

ADG465 Re-design and Wafer Fabrication Transfer

Qualification Results Summary of ADG465 at ADI-Limerick Fab

QUALIFICATION RESULT			
TEST	SPECIFICATION	SAMPLE SIZE	RESULT
Early Life Failure Rate (ELFR)	MIL-STD-883 M1015	3 x 667	PASS
High Temperature Storage (HTS)	JEDEC <i>JESD22-A103</i>	3 x 77	PASS
High Temperature Operating Life (HTOL)*	JEDEC <i>JESD22-A102</i>	3 x 77	PASS
Latch-Up	JEDEC <i>JESD78</i>	1 x 6	PASS
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JS-001-2011</i>	3/voltage	PASS $\pm 400V$
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	3/voltage	PASS $\pm 1250V$

*Preconditioned per JEDEC/IPC J-STD-020